

# Low-Power Bidirectional I<sup>2</sup>C Isolators

Check for Samples: ISO1540, ISO1541

#### **FEATURES**

- Isolated Bidirectional, I<sup>2</sup>C Compatible, Communications
- Supports up to 1 MHz Operation
- 3-V to 5.5-V Supply Range
- Open Drain Outputs with 3.5-mA Side 1 and 35-mA Side 2 Sink Current Capability
- -40°C to 125°C Operating Temperature
- ±50 kV/µs Transient Immunity (Typical)
- HBM ESD Protection of 4 kV on All Pins: 8 kV on Bus Pins

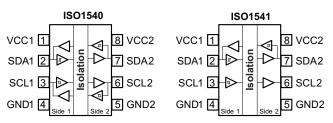
## APPLICATIONS

- Isolated I<sup>2</sup>C Bus
- **SMBus and PMBus Interfaces**
- **Open-drain Networks**
- Motor Control Systems
- **Battery Management** .
- I<sup>2</sup>C Level Shifting

#### DESCRIPTION

#### SAFETY AND REGULATORY APPROVALS

- 4000-V<sub>PK</sub> Isolation per DIN EN 60747-5-2 (VDE 0884 Part 2) (Approved)
- 2500-V<sub>RMS</sub> Isolation for 1 minute per UL 1577 (Approved)
- **CSA** Component Acceptance Notice 5A (Approved)
- IEC 60950-1 and IEC 61010-1 End Equipment Standards (Approved)



The ISO1540 and ISO1541 are low-power, bidirectional isolators that are compatible with I2C interfaces. These devices have their logic input and output buffers separated by TI's Capacitive Isolation technology using a silicon dioxide (SiO2) barrier. When used in conjunction with isolated power supplies, these devices block high voltages, isolate grounds, and prevent noise currents from entering the local ground and interfering with or damaging sensitive circuitry.

This isolation technology provides for function, performance, size, and power consumption advantages when compared to opto-couplers. The ISO1540 and ISO1541 enable a complete isolated I<sup>2</sup>C interface to be implemented within a small form factor.

The ISO1540 has two isolated bidirectional channels for clock and data lines while the ISO1541 has a bidirectional data and a unidirectional clock channel. The ISO1541 is useful in applications that have a single Master while the ISO1540 is ideally fit for multi-master applications.

Isolated bidirectional communications is accomplished within these devices by offsetting the Side 1 Low-Level Output Voltage to a value greater than the Side 1 High-Level Input Voltage thus preventing an internal logic latch that otherwise would occur with standard digital isolators.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet. I<sup>2</sup>C is a trademark of NXP B.V Corporation.

#### **ISO1540** ISO1541 SLLSEB6B-JULY 2012-REVISED MAY 2013



www.ti.com



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### **PIN FUNCTIONS**

ISO1540 and ISO1541	1/0	DESCRIPTION			
NAME	PIN	ISO1540	ISO1541	ISO1540	ISO1541
VCC1	1	-	-	Supply Voltage, Side 1	Supply Voltage, Side 1
SDA1	2	I/O	1/0	Serial Data, Side 1 Input/Output	Serial Data, Side 1 Input/Output
SCL1	3	I/O	I	Serial Clock Input/Output, Side 1	Serial Clock Input, Side 1
GND1	4	-	-	Ground, Side 1	Ground, Side 1
GND2	5	-	-	Ground, Side 2	Ground, Side 2
SCL2	6	I/O	0	Serial Clock Input/Output, Side 2	Serial Clock Output, Side 2
SDA2	7	I/O	1/0	Serial Data Input/Output, Side 2	Serial Data Input/Output, Side 2
VCC2	8	-	-	Supply Voltage, Side 2	Supply Voltage, Side 2

#### **AVAILABLE OPTIONS**

PRODUCT	RATED ISOLATION	PACKAGE	CHANNEL DIRECTION	MARKED AS	ORDERING NUMBER
ISO1540			Both SDA and SCL IS1540		ISO1540D (rail)
	4000-V <sub>PK</sub> and	D-8	are Bidirectional	131340	ISO1540DR (reel)
1001541	2500-V <sub>RMS</sub> <sup>(1)</sup>		SDA is Bidirectional	IS1541	ISO1541D (rail)
ISO1541			SCL is Unidirectional	151541	ISO1541DR (reel)

(1) See the Regulatory Information table for detailed Isolation specifications.

#### Table 1. FUNCTION TABLE<sup>(1)</sup>

POWER STATE	INPUT	OUTPUT
VCC1 or VCC2 < 2.1 V	Х	Z
VCC1 and VCC2 > 2.8 V	L	L
VCC1 and VCC2 > 2.8 V	Н	Z
VCC1 and VCC2 > 2.8 V	Z <sup>(2)</sup>	?

(1) H = High Level; L = Low Level; Z = High Impedance or Float; X = Irrelevant; ? = Indeterminate (2) Invalid input condition as an  $I^2C$  system requires that a pull-up resistor to VCC is connected.

Copyright © 2012-2013, Texas Instruments Incorporated

#### ABSOLUTE MAXIMUM RATINGS (1)(2)

				VAL	UES	UNIT
				MIN	MAX	
	VCC1, VCC2			-0.5	6	V
Supply voltage	SDA1, SCL1			-0.5	VCC1 + 0.5	V
	SDA2, SCL2	SDA2, SCL2				V
	SDA1, SCL1				±20	mA
Output current	SDA2, SCL2		±100	mA		
	Liver on Dady Madel		Bus Pins		±8	kV
Flastrastatia	Human Body Model	ESDA, JEDEC JS-001-2012	All Pins		±4	
Electrostatic Discharge	Field-Induced-Charged Device Model	JEDEC JESD22-C101E All Pins			±1.5	kV
	Machine Model	JEDEC JESD22-A115-A			±200	V
T <sub>J(MAX)</sub>	Maximum junction temperature				150	°C
T <sub>STG</sub>	Storage temperature range	9		-65	150	°C

(1) Stresses beyond those listed under ABSOLUTE MAXIMUM RATINGS cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under RECOMMENDED OPERATING CONDITIONS is not implied. Exposure to absolute-maximum-rated conditions for extended periods affects device reliability.

(2) All voltage values here within are with respect to the local ground terminal (GND1 or GND2) and are peak voltage values.

#### THERMAL INFORMATION

	THERMAL METRIC <sup>(1)</sup>	ISO1540 ISO1541	UNITS	
		D (8 PINS)		
$\theta_{JA}$	Junction-to-ambient thermal resistance	114.6		
θ <sub>JCtop</sub>	Junction-to-case (top) thermal resistance	69.6		
θ <sub>JB</sub>	Junction-to-board thermal resistance	55.3	8 <b>0</b> AA	
Ψυτ	Junction-to-top characterization parameter	27.2	°C/W	
Ψ <sub>JB</sub>	Junction-to-board characterization parameter	54.7		
θ <sub>JCbot</sub>	Junction-to-case (bottom) thermal resistance	n/a		

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

## **RECOMMENDED OPERATING CONDITIONS**

		MIN	NOM MAX	UNIT
VCC1, VCC2	Supply Voltage	3	5.5	
V <sub>SDA1</sub> , V <sub>SCL1</sub>	Input/Output Signal Voltages, Side 1	0	VCC1	
V <sub>SDA2</sub> , V <sub>SCL2</sub>	Input/Output Signal Voltages, Side 2	0	VCC2	
V <sub>IL1</sub>	Low-Level Input Voltage, Side 1	0	0.5	V
V <sub>IH1</sub>	High-Level Input Voltage, Side 1	0.7 x VCC1	VCC1	
V <sub>IL2</sub>	Low-Level Input Voltage, Side 2	0	0.3 x VCC2	
V <sub>IH2</sub>	High-Level Input Voltage, Side 2	0.7 x VCC2	VCC2	
I <sub>OL1</sub>	Output Current, Side 1	0.5	3.5	mA
I <sub>OL2</sub>	Output Current, Side 2	0.5	35	IIIA
C <sub>b1</sub>	Maximum Capacitive Load, Side 1		40	<b>»</b> ۲
C <sub>b2</sub>	Maximum Capacitive Load, Side 2		400	pF
f <sub>MAX</sub>	Maximum Operating Frequency (1)		1	MHz
T <sub>A</sub>	Ambient Temperature	-40	125	°C
TJ	Junction Temperature	-40	136	°C
T <sub>SD</sub>	Thermal Shutdown	139	171	°C

(1) This represents the maximum frequency with the maximum bus load (C<sub>b</sub>) and the maximum current sink (I<sub>0</sub>). If the system has less bus capacitance, then higher frequencies can be achieved.

SLLSEB6B-JULY 2012-REVISED MAY 2013



www.ti.com

#### **ELECTRICAL CHARACTERISTICS**

Over recommended operating conditions, unless otherwise noted

	PARAMETER		TEST	CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY CU	RRENT (3V ≤ VCC1, VCC	2 ≤ 3.6V)						
1	Supply Current, Side 1	ISO1540	V <sub>SDA1</sub> ,			2.4	3.6	
I <sub>CC1</sub>	Supply Current, Side 1	ISO1541	V <sub>SCL1</sub> = GND1;			2.1	3.3	
I <sub>CC2</sub>	Supply Current, Side 2	ISO1540 and ISO1541	V <sub>SDA2</sub> , V <sub>SCL2</sub> = GND2	See Figure 1;		1.7	2.7	1
1	Quantu Quanant Qida 4	ISO1540	V <sub>SDA1</sub> ,	$R_1, R_2 = Open,$ $C_1, C_2 = Open$		2.5	3.8	mA
I <sub>CC1</sub>	Supply Current, Side 1	ISO1541	V <sub>SCL1</sub> = VCC1;			2.3	3.6	
I <sub>CC2</sub>	Supply Current, Side 2	ISO1540 and ISO1541	V <sub>SDA2</sub> , V <sub>SCL2</sub> = VCC2			1.9	3.1	
SUPPLY CU	RRENT (4.5 V ≤ VCC1, VC	CC2 ≤ 5.5 V)						
1	Quantu Quanant Qida 4	ISO1540	V <sub>SDA1</sub> ,			3.1	4.7	
I <sub>CC1</sub>	Supply Current, Side 1	ISO1541	V <sub>SCL1</sub> = GND1;			2.8	4.4	
I <sub>CC2</sub>	Supply Current, Side 2	ISO1540 and ISO1541	V <sub>SDA2</sub> , V <sub>SCL2</sub> = GND2	See Figure 1;		2.3	3.7	
		ISO1540	V <sub>SDA1</sub> ,	$R_1, R_2 = Open,$ $C_1, C_2 = Open$		3.1	4.7	mA
I <sub>CC1</sub>	Supply Current, Side 1	ISO1541	V <sub>SCL1</sub> = VCC1;	- 1,-2 - 1		2.9	4.5	
I <sub>CC2</sub>	Supply Current, Side 2	ISO1540 and ISO1541	V <sub>SDA2</sub> , V <sub>SCL2</sub> = VCC2			2.5	4	
	PARAM	IETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SIDE 1 (Only	/)						1	
V <sub>ILT1</sub>	Voltage Input Threshold Side 1 (SDA1, SCL1)	"Low",			500	550	660	
V <sub>IHT1</sub>	Voltage Input Threshold Side 1 (SDA1, SCL1)	"High",			540	610	700	
V <sub>HYST1</sub>	Voltage Input Hysteresis Side 1 V <sub>IHT1</sub> - V <sub>ILT1</sub>	З,			40	60		mV
V <sub>OL1</sub> <sup>(1)</sup>	Low-Level Output Voltag Side 1 (SDA1,SCL1)	ge,		— 0.5 mA ≤ (I <sub>SDA1</sub> and I <sub>SCL1</sub> ) ≤ 3.5 mA	650		800	
$\Delta V_{OIT1}$ <sup>(1)(2)</sup>	Low-Level Output Voltag Threshold Difference, Side 1 (SDA1, SCL1)	ge to High-Level I	nput Voltage		50			
SIDE 2 (Only	/)							
V <sub>ILT2</sub>	Voltage Input Threshold Side 2 (SDA2, SCL2)	"Low",			0.3 x VCC2		0.4 x VCC2	
V <sub>IHT2</sub>	Voltage Input Threshold Side 2 (SDA2, SCL2)	"High",			0.4 x VCC2		0.5 x VCC2	
V <sub>HYST2</sub>	Voltage Input Hysteresis Side 2 V <sub>IHT2</sub> - V <sub>ILT2</sub>	З,			0.05 x VCC2			mV
V <sub>OL2</sub>	Low-Level Output Voltage, Side 2 (SDA2, SCL2)		0.5 mA ≤ ( $I_{SDA2}$ and $I_{SCL2}$ ) ≤ 35 mA			400		
BOTH SIDES	6							
1,	Input Leakage Currents (SDA1, SCL1, SDA2, SO	CL2)		$V_{SDA1}$ , $V_{SCL1} = VCC1$ ; $V_{SDA2}$ , $V_{SCL2} = VCC2$		0.01	10	μA
CI	Input Capacitance to Lo (SDA1, SCL1, SDA2, So			V <sub>I</sub> = 0.4 x sin(2E6πt) + 2.5 V		7		pF
CMTI	Common-Mode Transier	nt Immunity		See Figure 3	25	50		kV/µs
V <sub>CCUV</sub> <sup>(3)</sup>	V <sub>CC</sub> Undervoltage Locko (Side 1 and Side 2)	out Threshold			2.1	2.5	2.8	V

(1)

This parameter does not apply to the ISO1541 SCL1 line as it is uni-directional.  $\Delta V_{OIT1} = V_{OL1} - V_{IHT1}$ . This represents the minimum difference between a Low-Level Output Voltage and a High-Level Input Voltage (2) Threshold to prevent a permanent latch condition that would otherwise exist with bi-directional communication.

Any V<sub>CC</sub> voltages, on either side, less than the minimum will ensure device lockout. Both V<sub>CC</sub> voltages above the maximum will prevent (3) device lockout.



SWITCHING CHARACTERISTICS

Over recommended operating conditions, unless otherwise noted

	PARAMETER	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
3 V ≤ VCC1	, VCC2 ≤ 3.6 V						
	Output Signal Fall Time	See Figure 1	0.7 x VCC1 to 0.3 x VCC1	8	17	29	
t <sub>f1</sub>	(SDA1, SCL1)	$R_1 = 953 \Omega,$ $C_1 = 40 \text{ pF}$	0.9 x VCC1 to 900 mV	16	29	48	ns
	Output Signal Fall Time	See Figure 1	0.7 x VCC2 to 0.3 x VCC2	14	23	47	
t <sub>f2</sub>	(SDA2, SCL2)	R <sub>2</sub> = 95.3 Ω, C <sub>2</sub> = 400 pF	0.9 x VCC2 to 400 mV	35	50	100	ns
t <sub>pLH1-2</sub>	Low-to-High Propagation Delay, Side 1 to Side 2		0.55 V to 0.7 x VCC2		33	65	ns
t <sub>PHL1-2</sub>	High-to-Low Propagation Delay, Side 1 to Side 2	_	0.7 V to 0.4 V		90	181	ns
PWD <sub>1-2</sub>	Pulse Width Distortion  t <sub>pHL1-2</sub> – t <sub>pLH1-2</sub>	See Figure 1 $R_1 = 953 \Omega$ ,			55	123	ns
t <sub>PLH2-1</sub> (1)	Low-to-High Propagation Delay, Side 2 to Side 1	$R_2 = 95.3 \Omega,$ $C_1, C_2 = 10 \text{ pF}$	0.4 x VCC2 to 0.7 x VCC1		47	68	ns
t <sub>PHL2-1</sub> <sup>(1)</sup>	High-to-Low Propagation Delay, Side 2 to Side 1		0.4 x VCC2 to 0.9 V		67	109	ns
PWD <sub>2-1</sub> <sup>(1)</sup>	Pulse Width Distortion  t <sub>pHL2-1</sub> – t <sub>pLH2-1</sub>				20	49	ns
t <sub>LOOP1</sub> <sup>(1)</sup>	Round-trip propagation delay on Side 1	See Figure 2; $R_1 = 953 \Omega$ , $C_1 = 40 pF$ $R_2 = 95.3 \Omega$ , $C_2 = 400 pF$	0.4 V to 0.3 x VCC1		100	165	ns
4.5V ≤ VCC	1, VCC2 ≤ 5.5V			L			
	Output Signal Fall Time	See Figure 1	0.7 x VCC1 to 0.3 x VCC1	6	11	20	
t <sub>f1</sub>	(SDA1, SČL1)	$R_1 = 1430 \Omega,$ $C_1 = 40 \text{ pF}$	0.9 x VCC1 to 900 mV	13	21	39	ns
	Output Signal Fall Time	See Figure 1	0.7 x VCC2 to 0.3 x VCC2	10	18	35	
t <sub>f2</sub>	(SDA2, SCL2)	$R_2 = 143 \Omega,$ $C_2 = 400 \text{ pF}$	0.9 x VCC2 to 400 mV	28	41	76	ns
t <sub>pLH1-2</sub>	Low-to-High Propagation Delay, Side 1 to Side 2		0.55 V to 0.7 x VCC2		31	62	ns
t <sub>PHL1-2</sub>	High-to-Low Propagation Delay, Side 1 to Side 2		0.7 V to 0.4 V		70	139	ns
PWD <sub>1-2</sub>	Pulse Width Distortion  t <sub>pHL1-2</sub> – t <sub>pLH1-2</sub>	See Figure 1 $R_1 = 1430 \Omega$ ,			38	80	ns
t <sub>PLH2-1</sub> <sup>(1)</sup>	Low-to-High Propagation Delay, Side 2 to Side 1	$R_2 = 143 \Omega,$ C <sub>1, 2</sub> = 10 pF	0.4 x VCC2 to 0.7 x VCC1		55	80	ns
t <sub>PHL2-1</sub> <sup>(1)</sup>	High-to-Low Propagation Delay, Side 2 to Side 1		0.4 x VCC2 to 0.9 V		47	85	ns
PWD <sub>2-1</sub> <sup>(1)</sup>	Pulse Width Distortion  t <sub>pHL2-1</sub> – t <sub>pLH2-1</sub>				8	21	ns
t <sub>LOOP1</sub> <sup>(1)</sup>	Round-trip propagation delay on Side 1	See Figure 2; $R_1 = 1430 \Omega$ , C1 = 40 pF $R_2 = 143 \Omega$ , C2 = 400 pF	0.4 V to 0.3 x VCC1		110	180	ns

(1) This parameter does not apply to the ISO1541 SCL1 line as it is uni-directional.

#### **TIMING CHARACTERISTICS**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>SP</sub>	Input Noise Filter		5	12		ns
t <sub>UVLO</sub>	Time to recover from Undervoltage Lock-out	See Figure 4 2.7 V to 0.9 V	30	50	110	μs

TEXAS INSTRUMENTS

www.ti.com

#### PARAMETER MEASUREMENT INFORMATION

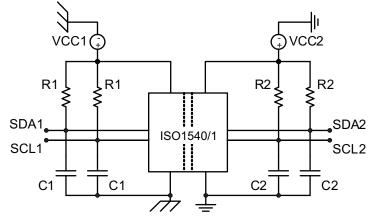
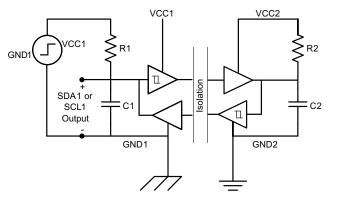


Figure 1. Test Diagram



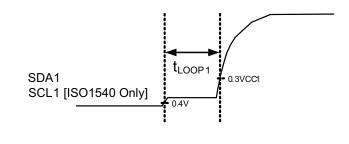


Figure 2. t<sub>Loop1</sub> Setup and Timing Diagram

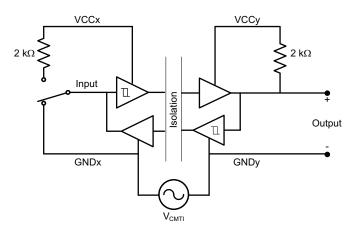
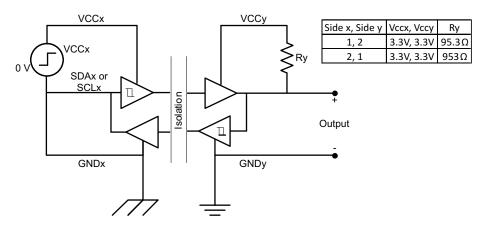
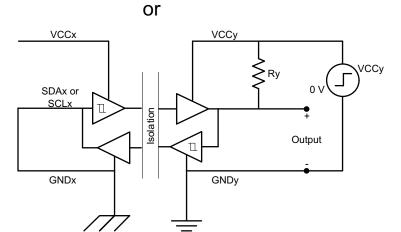


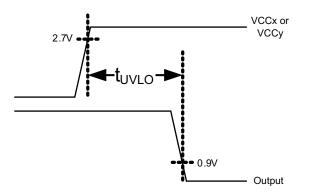
Figure 3. Common-Mode Transient Immunity Test Circuit

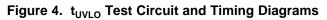


#### PARAMETER MEASUREMENT INFORMATION (continued)









#### **DEVICE INFORMATION**

# Table 2. IEC INSULATION AND SAFETY-RELATED SPECIFICATION FOR D-8 PACKAGE Over recommended operating conditions, unless otherwise noted

PARAMETER		TEST CONDITIONS	MIN TYP MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	4.8	mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	4.3	mm
СТІ	Tracking resistance (comparative tracking index)	DIN IEC 60112 / VDE 0303 Part 1	>400	V
	Minimum internal gap (internal clearance)	Distance through the insulation	0.014	mm
-	Isolation resistance, input to	V <sub>IO</sub> = 500 V, T <sub>A</sub> < 100°C	>10 <sup>12</sup>	Ω
R <sub>IO</sub>	output <sup>(1)</sup>	$V_{IO} = 500 \text{ V}, 100^{\circ}\text{C} \le \text{T}_{\text{A}}$	>10 <sup>11</sup>	Ω
C <sub>IO</sub>	Barrier capacitance, input to output <sup>(1)</sup>	$V_{IO} = 0.4 \text{ x} \sin(2E6\pi t)$	1	pF
CI	Input capacitance <sup>(2)</sup>		See Electrical Characteristics	pF

(1) All pins on each side of the barrier tied together creating a two-terminal device.

(2) Measured from input pin to ground.

#### NOTE

Creepage and clearance requirements should be applied according to the specific application isolation standards. Care should be taken to maintain these distances on a board design to ensure that the mounting pads for the isolator do not reduce this distance.

Creepage and clearance on the printed-circuit board become equal in certain cases. Techniques such as inserting grooves and/or ribs on the printed circuit board are used to help increase these specifications.

#### Table 3. IEC 60747-5-2 INSULATION CHARACTERISTICS<sup>(1)</sup> Over recommended operating conditions, unless otherwise noted

PARAMETER		TEST CONDITIONS	SPECIFICATION	UNIT
V <sub>IORM</sub>	Maximum working insulation voltage		566	
		Method a, After environmental tests subgroup 1, $V_{PR} = V_{IORM} \times 1.6$ , t = 10 sec, Partial Discharge < 5 pC	906	
V <sub>PR</sub>	Input-to-Output test voltage per IEC 60747-5-2	Method b1, After environmental tests subgroup 1, $V_{PR} = V_{IORM} \times 1.875$ , t = 1 sec (100% production), Partial Discharge < 5 pC	1062	V <sub>PEAK</sub>
		After Input/Output safety test subgroup 2/3, $V_{PR} = V_{IORM} \times 1.2$ , t = 10 sec, Partial Discharge < 5 pC	680	
V <sub>IOTM</sub>	Transient overvoltage per IEC 60747-5-2	V <sub>TEST</sub> = V <sub>OITM</sub> t = 60 sec (qualification) t = 1 sec (100% production)	4000	
R <sub>S</sub>	Insulation resistance	$V_{IO} = 500 \text{ V at } T_S$	>10 <sup>9</sup>	Ω
	Pollution degree		2	

(1) Climatic Classification 40/125/21



#### Table 4. IEC 60664-1 RATINGS TABLE

PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	sic isolation group Material group	
	Rated mains voltage ≤ 150 V <sub>RMS</sub>	I–IV
Installation classification	Rated mains voltage ≤ 300 V <sub>RMS</sub>	I—III
	Rated mains voltage ≤ 400 V <sub>RMS</sub>	I—II

#### Table 5. REGULATORY INFORMATION

VDE	CSA	UL
Certified according to DIN EN 60747-5-2 (VDE 0884 Part 2) and EN 61010-1	Approved under CSA Component Acceptance Notice 5A, CSA/IEC 60950-1 and CSA/IEC 61010-1	Recognized under UL 1577 Component Recognition Program
Basic Insulation Maximum Transient Overvoltage, 4000 V <sub>PK</sub> Maximum Surge Voltage, 4000 V <sub>PK</sub> Maximum Working Voltage, 566 V <sub>PK</sub>	Basic insulation per CSA 60950-1-07 and IEC 60950-1 (2nd Ed), 390 $V_{RMS}$ maximum working voltage Basic insulation per CSA 61010-1-04 and IEC 61010-1 (2nd Ed), 300 $V_{RMS}$ maximum working voltage Reinforced insulation per CSA 61010-1-04 and IEC 61010-1 (2nd Ed), 150 $V_{RMS}$ maximum working voltage voltage	Single Protection Isolation Voltage, 2500 $V_{RMS}^{(1)}$
File number: 40016131	File number: 220991	File number: E181974

(1) Production tested  $\ge$  3000 V<sub>RMS</sub> for 1 second in accordance with UL 1577.

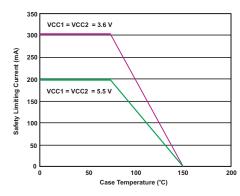
## IEC SAFETY LIMITING VALUES

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the IO can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Safety input, output, or supply	D-8	$\theta_{JA} = 114.6^{\circ}C/W, V_{I} = 5.5V, T_{J} = 150^{\circ}C, T_{A} = 25^{\circ}C$			198	<b>m</b> 1
<sup>IS</sup> current	current	D-0	$\theta_{JA} = 114.6^{\circ}C/W, V_{I} = 3.6V, T_{J} = 150^{\circ}C, T_{A} = 25^{\circ}C$			303	mA
$T_S$	Maximum case temperature					150	°C

The safety-limiting constraint is the absolute maximum junction temperature specified in the absolute maximum ratings table. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the *Thermal Information* table is that of a device installed on a High-K Test Board for Leaded Surface Mount Packages. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

**ISO154x THERMAL DERATING** 





ISO1541 SLLSEB6B – JULY 2012–REVISED MAY 2013



www.ti.com

#### **APPLICATION INFORMATION**

#### I<sup>2</sup>C<sup>™</sup> Bus Overview

ISO1540

The I<sup>2</sup>C (Inter-Integrated Circuit) bus is a single-ended, multi-master, 2-wire bus for efficient inter-IC communication in half-duplex mode.

I<sup>2</sup>C uses open-drain technology, requiring two lines, Serial Data (SDA) and Serial Clock (SCL), to be connected to VDD by resistors (see Figure 6). Pulling the line to ground is considered a logic Zero while letting the line float is a logic One. This is used as a channel access method. Transitions of logic states must occur while SCL is Low, transitions while SCL is high indicate START and STOP conditions. Typical supply voltages are 3.3 V and 5 V, although systems with higher or lower voltages are permitted.

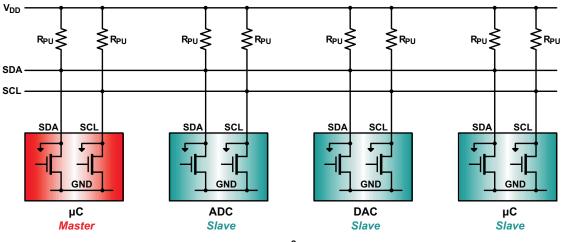


Figure 6. I<sup>2</sup>C BUS

I<sup>2</sup>C communication uses a 7-bit address space with 16 reserved addresses, so a theoretical maximum of 112 nodes can communicate on the same bus. In praxis, however, the number of nodes is limited by the specified, total bus capacitance of 400 pF, which restricts communication distances to a few meters.

The specified signaling rates for the ISO1540 and ISO1541 are 100 kbps (Standard mode), 400 kbps (Fast mode), 1 Mbps (Fast mode plus).

The bus has two roles for nodes: master and slave. A master node issues the clock, slave addresses, and also initiates and ends data transactions. A slave node receives the clock and addresses and responds to requests from the master. Figure 7 shows a typical data transfer between master and slave.

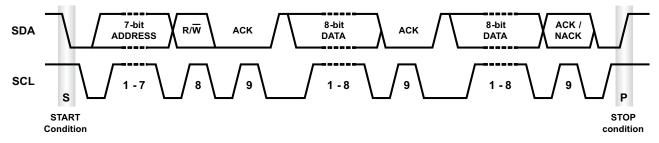


Figure 7. Timing Diagram of a Complete Data Transfer

The master initiates a transaction by creating a START condition, following by the 7-bit address of the slave it wishes to communicate with. This is followed by a single Read/Write bit, representing whether the master wishes to write to (0), or to read from (1) the slave. The master then releases the SDA line to allow the slave to acknowledge the receipt of data.

The slave responds with an acknowledge bit (ACK) by pulling SDA low during the entire high time of the 9th clock pulse on SCL, after which the master continues in either transmit or receive mode (according to the R/W bit sent), while the slave continues in the complementary mode (receive or transmit, respectively).



The address and the 8-bit data bytes are sent most significant bit (MSB) first. The START bit is indicated by a high-to-low transition of SDA while SCL is high. The STOP condition is created by a low-to-high transition of SDA while SCL is high.

If the master writes to a slave, it repeatedly sends a byte with the slave sending an ACK bit. In this case, the master is in master-transmit mode and the slave is in slave-receive mode.

If the master reads from a slave, it repeatedly receives a byte from the slave, while acknowledging (ACK) the receipt of every byte but the last one (see Figure 8). In this situation the master is in master-receive mode and the slave is in slave-transmit mode.

The master ends the transmission with a STOP bit, or may send another START bit to maintain bus control for further transfers.

	S Slave Address WA	DATA	Α	DATA	A P	A = acknowledge				
From Master to Slave	Master Transn	nitter writing	to Slave	Receiver		A = not acknowledge S = Start				
From Slave to Master										
	S Slave Address R A	DATA	Α	DATA	ĀP	R = Read				
	W = Write									

Figure 8. Transmit or Receive Mode Changes During a Data Transfer

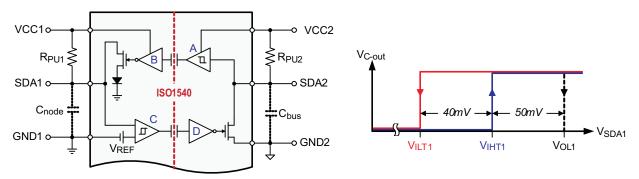
When writing to a slave, a master mainly operates in transmit-mode and only changes to receive-mode when receiving acknowledgment from the slave.

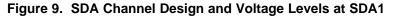
When reading from a slave, the master starts in transmit-mode and then changes to receive-mode after sending a READ request (R/W bit = 1) to the slave. The slave continues in the complementary mode until the end of a transaction.

Note, that the master ends a reading sequence by not acknowledging (NACK) the last byte received. This procedure resets the slave state machine and allows the master to send the STOP command.

#### Isolator Functional Principle

To isolate a bidirectional signal path (SDA or SCL), the ISO1540 internally splits a bidirectional line into two unidirectional signal lines, each of which is isolated via a single-channel digital isolator. Each channel output is made open-drain to comply with the open-drain technology of  $I^2C$ . Side 1 of the ISO1540 connects to a low-capacitance  $I^2C$  node, while Side 2 is designed for connecting to a fully loaded  $I^2C$  bus with up to 400 pF capacitance.





At first sight, the arrangement of the internal buffers suggests a closed signal loop that is prone to latch-up. However, this loop is broken by implementing an output buffer (B) whose output low-level is raised by a diode drop to approximately 0.75 V, and the input buffer (C) that consists of a comparator with defined hysteresis. The comparator's upper and lower input thresholds then distinguish between the proper low-potential of 0.4 V maximum driven directly by SDA1 and the buffered output low-level of B.

Copyright © 2012–2013, Texas Instruments Incorporated

Figure 10 demonstrate the switching behavior of the I<sup>2</sup>C isolator, ISO1540, between a master node at SDA1 and a heavy loaded bus at SDA2

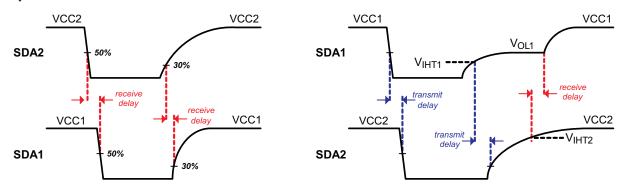


Figure 10. SDA Channel Timing in Receive and Transmit Directions

#### **Receive Direction (left diagram)**

When the l<sup>2</sup>C bus drives SDA2 low, SDA1 follows after a certain delay in the receive path. Its output low will be the buffered output of  $V_{OL1} = 0.75$  V, which is sufficiently low to be detected by Schmitt-trigger inputs with a minimum input-low voltage of  $V_{IL} = 0.9$  V at 3 V supply levels.

Once SDA2 is released, its voltage potential increases towards VCC2 following the time-constant formed by  $R_{PU2}$  and  $C_{bus}$ . After the receive delay, SDA1 is released and also rises towards VCC1, following the time-constant  $R_{PU1} \times C_{node}$ . Because of the significant lower time-constant, SDA1 may reach VCC1 before SDA2 reaches VCC2 potential.

#### Transmit Direction (right diagram)

When a master drives SDA1 low, SDA2 follows after a certain delay in the transmit direction. When SDA2 turns low it also causes the output of buffer B to turn low but at a higher 0.75 V level. This level cannot be observed immediately as it is overwritten by the master's lower low-level.

However, when the master releases SDA1, its voltage potential increases and first must pass the upper input threshold of the comparator,  $V_{IHT1}$ , to release SDA2. SDA1 then increases further until it reaches the buffered output level of  $V_{OL1} = 0.75$  V, maintained by the receive path. Once comparator C turns high, SDA2 is released after the delay in transmit direction. It takes another receive delay until B's output turns high and fully releases SDA1 to move towards VCC1 potential.



#### **Typical Application Circuit**

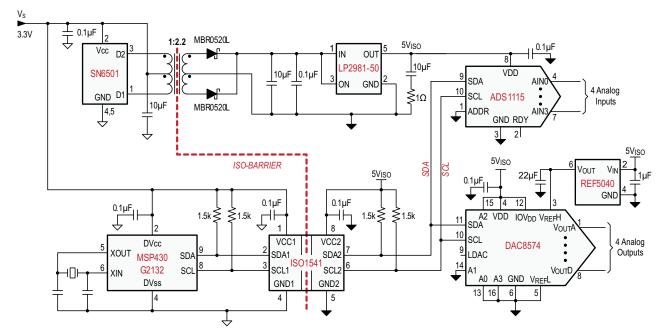
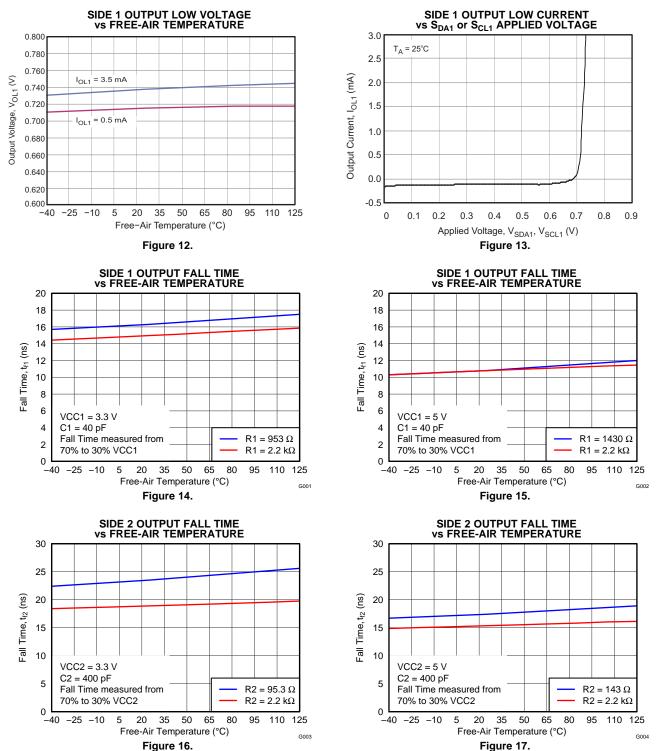


Figure 11. Isolated I<sup>2</sup>C Data Acquisition System

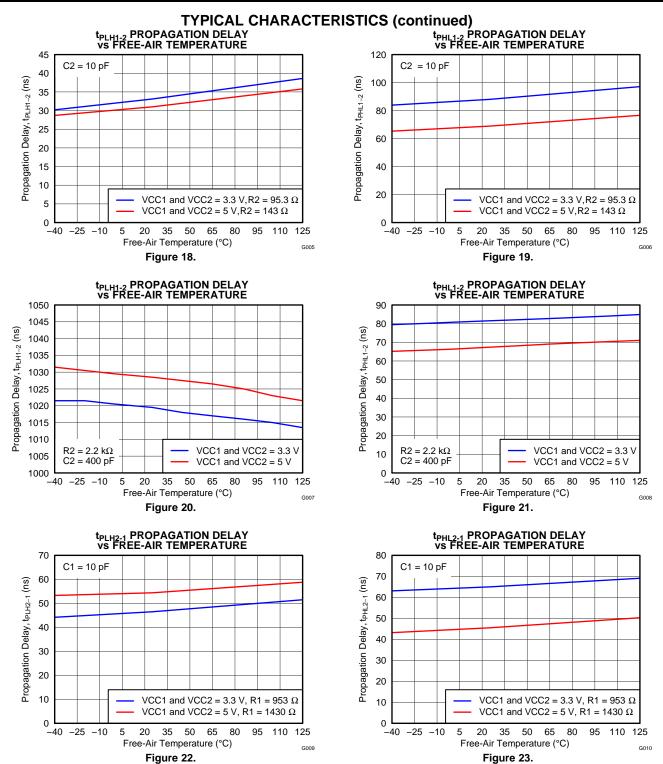
In Figure 11, the ultra low-power micro controller, MSP430G2132, controls the I<sup>2</sup>C data traffic of configuration data and conversion results for the analog inputs and outputs. Low-power data converters build the analog interface to sensors and actuators. The ISO1541 provides the necessary isolation between different ground potentials of the system controller, remote sensor, and actuator circuitry to prevent ground loop currents that otherwise may falsify the acquired data.

The entire circuit operates from a single 3.3 V supply. A low-power push-pull converter, SN6501, drives a centertapped transformer whose output is rectified and linearly regulated to provide a stable 5 V supply for the data converters.

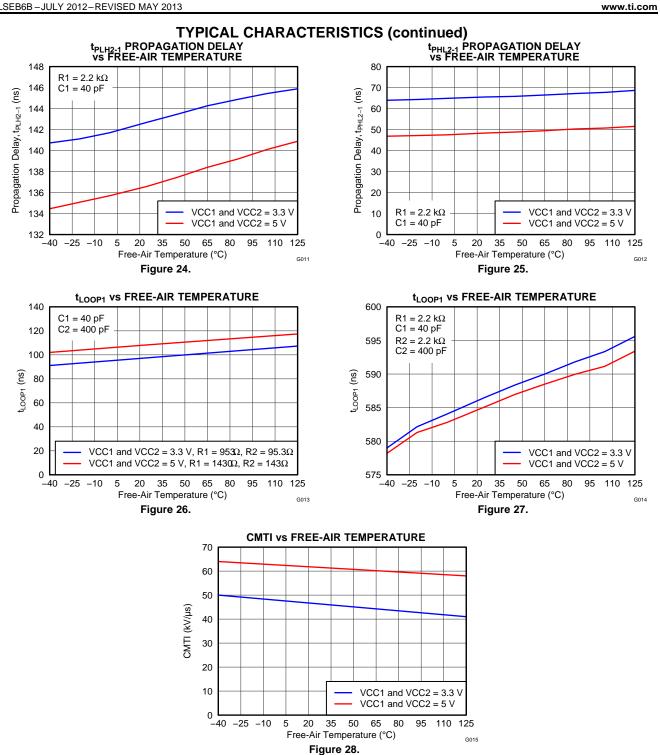








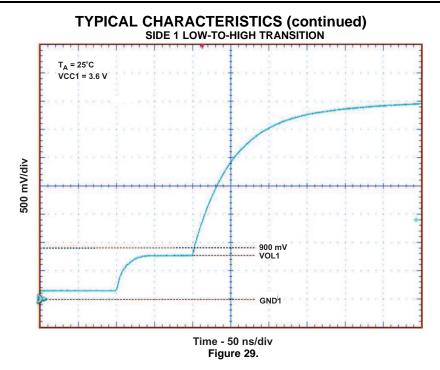
ISO1540 ISO1541
SUI SEB6B - IUII V 2012-REVISED MAY 201



**Texas** 

**INSTRUMENTS** 





#### **REVISION HISTORY**

C	hanges from Original (July 2012) to Revision A	Page
•	Changed From: CSA Component Acceptance Notice 5A (Pending) To: CSA Component Acceptance Notice 5A (Approved)	1
•	Changed From: IEC 60950-1 and IEC 61010-1 End Equipment Standards (Pending) To: IEC 60950-1 and IEC 61010-1 End Equipment Standards (Approved)	1
•	Changed Table 5, CSA column From: File number: 220991 (pending) To: File number: 220991	9
C	hanges from Original (October 2012) to Revision B	Page
•	Change Safety Feature From: (VDE 0884 Part 2) (Pending) To: (VDE 0884 Part 2) (Approved)	1
•	Changed, VDE column From: File number: 40016131 (pending) To: File number: 40016131	9



17-Apr-2013

### PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing		Qty	(2)		(3)		(4)	
ISO1540D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	IS1540	Samples
ISO1540DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	IS1540	Samples
ISO1541D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	IS1541	Samples
ISO1541DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	IS1541	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



PACKAGE OPTION ADDENDUM

17-Apr-2013

# PACKAGE MATERIALS INFORMATION

www.ti.com

Texas Instruments

#### TAPE AND REEL INFORMATION





### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO1540DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO1541DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

TEXAS INSTRUMENTS

www.ti.com

# PACKAGE MATERIALS INFORMATION

22-Oct-2013



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO1540DR	SOIC	D	8	2500	367.0	367.0	35.0
ISO1541DR	SOIC	D	8	2500	367.0	367.0	35.0

D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
   E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



#### **IMPORTANT NOTICE**

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconne	ectivity	

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2013, Texas Instruments Incorporated



# Authorized Distribution Brand :



## Website :

Welcome to visit www.ameya360.com

# Contact Us :

➤ Address :

401 Building No.5, JiuGe Business Center, Lane 2301, Yishan Rd Minhang District, Shanghai , China

- > Sales :
  - Direct +86 (21) 6401-6692
  - Email amall@ameya360.com
  - QQ 800077892
  - Skype ameyasales1 ameyasales2

# > Customer Service :

Email service@ameya360.com

# > Partnership :

Tel +86 (21) 64016692-8333

Email mkt@ameya360.com